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## **For Immediate Release**

Photo available at [http://www.jmicrotechnology.com/PRPictsFolder/LMS\\_91A.jpg](http://www.jmicrotechnology.com/PRPictsFolder/LMS_91A.jpg)

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### **LMS-91A Temperature Chuck Adapter Kit Available for J microTechnology's LMS-2709 Laboratory Microprobe Station**

*Adds temperature control and enhanced heat sink to probed test device*

**Portland, OR –September 26, 2006** – J microTechnology, Inc., specialists in electrical and mechanical test products for advanced semiconductor devices and packaging, introduces its LMS-91A temperature controlled chuck for its LMS-2709 Laboratory Microprobe Station. The chuck adds temperature control and enhanced heat sink capability on the test device to be probed enabling measurements at non ambient temperatures. The LMS-91A provides the advantage of low cost thermal electric (TE) temperature control to microprobe technology on bench-top test applications for scientists and engineers.

J microTechnology's chuck operates at a temperature range of below 0 degrees Celsius (C) to 130 degrees Celsius. The temperature changes at approximately 2 seconds per degree, with temperature stability at better than 0.2 degrees C. This allows rapid change in operating point temperature and a stable test condition. The chuck is isolated from the stage and microprobe station base to allow test of back-side active semiconductors.

Since all semiconductor devices are temperature sensitive and other materials have curie points, measurements at non ambient temperatures are important for fundamental characterization. The LMS-91A thermal electric controller offers simplicity, reliability, and flexibility for routine and occasional measurements. Control temperature accuracy and intuitive operation are inherent with this product.

The LMS-91A attaches directly to the translation stage of the LMS-2709. Its XYZ probe positioners are compatible to coplanar RF/microwave probes, triaxial, coaxial, and

unshielded DC needles. Test devices are held down by vacuum and manipulated in the same manner as on a non-temperature controlled chuck.

The LMS-2709 is a rugged and basic RF (and DC) probe station for research of advanced active and passive components and is also for educational training of university students in the discipline of microwave microprobing.

The LMS-91A sells for under \$7,500. Delivery is about 6 weeks.

### **About J microTechnology**

J microTechnology, Inc. is dedicated to the supply and distribution of accessory products for the electrical and mechanical test of advanced semiconductor devices and packaging products. The products supply a basic, but comprehensive set of accessories for precision testing and microprobing of non coplanar structures. Primary products include microprobing fixtures, "Personal Probe Stations", custom and standard ProbePoint™ product thin film adapter interface circuits, calibration standards substrates, and high performance laboratory test cables. Customers include systems integrators, semiconductor and semiconductor package manufacturers, and government and university laboratories worldwide for use in transistor (FET, PHEMT, etc.) characterization, multichip MIC/MMIC assembly production test point, electro-optic device test adapters, MEMS, nanoelectronics devices, biomedical sensors, and high performance and low cost package characterization. Started in 1992, J microTechnology is based in Portland, Oregon.

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